




<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/791,135	CHEN ET AL.	
	Examiner	Art Unit	
	Jinhee J. Lee	2831	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
174	99r			174	100	72a				
INTERNATIONAL CLASSIFICATION										
a	b	c	d							
				21/06						
				/						
				/						
				/						
				/						
Jinhee Lee (Assistant Examiner) (Date)				 DEAN A. REICHARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) (Date)				Total Claims Allowed: 16		
 Doran Evans 4/6/05 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig 3a, 3b, 4f	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant						<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47			
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
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	7		37	67		97	127		157	187			
	8		38	68		98	128		158	188			
	9		39	69		99	129		159	189			
	10		40	70		100	130		160	190			
	11		41	71		101	131		161	191			
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	27		57	87		117	147		177	207			
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	29		59	89		119	149		179	209			
	30		60	90		120	150		180	210			